



Atty. Dkt. No. 039153-0405 (F0945)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Uzodinma Okoroanyanwu et al.


Title: IMPROVING SEM INSPECTION  
AND ANALYSIS OF  
PATTERNED PHOTORESIST  
FEATURES

Appl. No.: 09/820,143

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Examiner: Mary A. El Shammaa

Art Unit: 2881

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AMENDMENT AND REPLY UNDER 37 CFR 1.111

Mail Stop NON-FEE AMENDMENT  
Commissioner for Patents  
P.O. Box 1450  
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This communication is responsive to the Non-Final Office Action dated August 6, 2003, concerning the above-referenced patent application.

**Amendments to the Specification** begin on page 2 of this document.

**Amendments to the Claims** are reflected in the listing of claims which begins on page 3 of this document.

**Amendments to the Drawings** begin on page 6 of this document, and include a copy of the Formal Drawings filed June 11, 2001.

**Remarks/Arguments** begin on page 7 of this document.

Please amend the application as follows: